

PUBLIKATIONEN PROF. DR.-ING. CHRISTIAN THOMAS

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Publikationen

Joachimsthaler, I., Heiderhoff, R., Balk, L. J. u. a.: Investigation of electron-beam-induced potentials with an SEM/SPM hybrid system. In: Scanning 26, no. 2 (2004). pp. 76-77.

Altes, A., Balk, L. J., Hartnagel, H. L. u. a.: Nanoscopic Evaluation of Micro-Systems. In: NDT.net: E-Journal of Nondestructive Testing 9, no. 10 (2004). p.655.

Thomas, C., Joachimsthaler, I., Heiderhoff, R. u. a.: Untersuchung von elektronenstrahl-induzierten Potentialen mit einem Rasterkraft-/ Rasterelektronen-mikroskop Hybridssystem. In: EDO Herbsttagung, 2004, Abstracts 35.

Thomas, C., Joachimsthaler, I., Heiderhoff, R. u. a.: Electron-beam-induced potentials in semiconductors: calculation and measurement with an SEM/SPM hybrid system. In: J. Phys. D: Appl. Phys. 37, no 20 (2004). 2785-2794.

Thomas, C., Heiderhoff, R., Balk, L. J.: Imaging of Ferroelectric Domains in Barium-titanate using Surface Acoustic Waves in an SEM/AFM Hybrid System. In: Physics, Chemistry and Application of Nanostructures (2005). pp. 254-257.

Thomas, C., Heiderhoff, R., Balk, L. J.: Acoustic near-field conditions in an ESEM / AFM hybrid system. In: Abstracts ICN+T No.248 (2006). p.66.

Balk, L. J., Heiderhoff, R., Phang, J. C. H., u. a.: Characterization of electronic materials and devices by scanning near-field microscopy. In: Appl. Phys. A 87, no. 3 (2007). pp. 443-449.

Thomas, C., Heiderhoff, R., Balk, L. J.: 200 femtometer sensitivity for near-field analysis of surface acoustic waves in a scanning electron / scanning probe microscope hybrid system. In: Appl. Phys. Lett. 90 (2007). 144106.

Thomas, C., Heiderhoff, R., Balk, L. J.: Acoustic near-field conditions in an ESEM / AFM hybrid system. In: J. Phys.: Conf. Ser. 61 (2007). 1180-1185.

Thomas, C., Heiderhoff, R., Balk, L. J.: 200-femtometer sensitivity detecting Surface Acoustic Waves by an SEM/SFM- Hybrid System. In: Physics, Chemistry and Application of Nanostructures (2007). pp.180-183.

Thomas, C., Heiderhoff, R., Balk, L. J.: Acoustic near-field imaging in an SEM/SPM hybrid system with 200femtometer sensitivity. In: J. Scann. Probe Microsc. 2 (2007). pp. 15–18.

Thomas, C., Edelmann, M., Lysenkov, D. u. a.: Correlative Light and Electron Microscopy (CLEM) for Characterization of Lithium Ion Battery Materials. In: Microsc. Microanal. 16, Suppl 2 (2010). pp. 784-785.

Husain, M., Thomas, C., Kirschmann, M. u. a.: Functional and Structural Investigation of Songbird Brain Projection Neurons with Shuttle and Find. In: Microsc. Microanal. 17, Suppl 2 (2011). pp. 242-243.

Oberti, D., Kirschmann, M. A., Hahnloser, R. H. R. u. a.: Correlative microscopy of songbird brain projection neurons for characterization of neural microcircuits. In: MC 2011 Proc. Vol.2 (2011), L3 P319.

Berenthaler, T., Hafner, C., Knoblauch, V. u. a.: Microscopic Investigations and Characterization of Lithium-Ion Batteries Using Correlative Light and Scanning Electron Microscopy. In: MC 2011 Proc. Vol.3 (2011), M1 P516.

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Elli, A. F., Thomas, C., Böker, C. u. a.: Korrelative Licht- und Elektronenmikroskopie (CLEM) – Anwendungsmöglichkeiten in Bio- und Materialwissenschaften. In: Optik & Photonik 7, no. 1 (2012). pp. 32-26.

Elli, A. F., Thomas, C., Wojek, C. u. a.: Correlative Light and Electron Microscopy – on the way from 2D towards 3D. In: Abstracts SSOM 3D-Symposium 2012, 19-20.